



Report No .:

EMC2006030

File reference No.: 2020-06-19

Applicant:

Product:

Charging Cable

Brand Name:

N/A

Model No.:

MC31

Test Standards: EN 55032:2015

EN61000-3-2:2014

EN 55024: 2010+A1:2015 EN 61000-3-3: 2013

Test result:

The EMC testing has been performed on the submitted samples and found in compliance with council EMC Directive 2014/30/EU.

Approved By

Terry Tang

Manager

Dated:

Jun. 19, 2020

Results appearing herein relate only to the sample tested The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519, 5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen, Guangdong China

Tel (755) 83448688

Fax (755) 83442996

Email: info@timeway-lab.com

Date: 2020-06-19



Special Statement:

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

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The testing quality system of our laboratory meets with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

CNAS-LAB Code: L2292

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

Date: 2020-06-19



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6.0 Product Labelling 39

Photo of testing 40

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1.0 General Details

1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

Test Location

All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES.

Room 512-519,5/F., East Tower, Building 4, Anhua Industrial Zone, Futian District, Shenzhen,

Guangdong China

Tel(086) 755-83448688 Fax (086) 755-83442996

No tests were sub-contracted.

1.2 Applicant Details

Applicant: Digiview Technology Limited

Address: West of F2, Building B1, Gaoxinjian Industrial Park, Fuyuan 1st Road, FuYong, Baoan,

Shenzhen

Telephone: +86-755-33530646

Fax: --

Manufacturer: Digiview Technology Limited

Address: West of F2, Building B1, Gaoxinjian Industrial Park, Fuyuan 1st Road, FuYong, Baoan,

Shenzhen

Telephone: +86-755-33530646

Fax: --

1.3 Description of EUT

Product: Charging Cable

Brand Name: N/A
Model Number: MC31

Adding Model Numb -Wer: N /A

Rating: -Remark: ---

1.4 Submitted Sample(s)

1 Sample

1.5 Test Duration

Date of Receipt of Test Item: June 12, 2020 Date of Test: June 12, 2020~ June 19, 2020

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1.6 Additional information of EUT

	Submitted	Not Available
User Manual		
Part List		
Circuit Diagram	\boxtimes	
Printed circuit board[PCB] Layout	\boxtimes	
Block Diagram		
7 Test Engineer	NA CA	

1.

The sample(s) tested by

Print Name: Leo Lau/ Engineer

This test report is not valid without personnel's signatures of SHENZHEN TIMEWAY TESTING LABORATORIES

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List of Measurement Equipment 2.0

2.1 **Conducted Emission Test**

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESH3	860905/006	RS	2020.06.01	1Year
Spectrum Analyzer	ESA-L1500A	US37451154	HP	2020.06.01	1Year
PULSE LIMITER	ESH3-Z2	100281	RS	2020.06.01	1Year
LISN	ESH3-Z5	100294	RS	2020.06.01	1Year
LISN	ESH3-Z5	100253	RS	2020.06.01	1Year

2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESVD	100008	RS	2020.06.01	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer	8595E	3441A00893	HP	2020.06.01	1Year
Amplifier	8447D	2727A05017	HP	2020.06.01	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2020.06.01	1Year

2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test System	PACS-1	72305	CI	2020.06.01	1Year
5K VA AC Power Source	5001iX	56060	CI	2020.06.01	N/A

2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2020.06.01	1Year

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2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2020.06.01	1Year
Power Meter	NRVS		RS	2020.06.01	1Year
Voltage Probe	URV5-Z2	100012	RS	2020.06.01	1Year
Voltage Probe	URV5-Z2	100013	RS	2020.06.01	1Year
Power Amplifier	150W1000	300999	AR	2020.06.01	1Year
Power Amplifier	25S1G4AM1	305993	AR	2020.06.01	1Year
Field Probe	CBL6111C	2576	Holaday	2020.06.01	1Year
Bilog Antenna	MCDC		Chase	2020.06.01	1Year

Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2020.06.01	1Year
Power Source	MV2616	0104-14	EM TEST	2020.06.01	1Year

2.7 Surge Test

Name	Model No.	Serial No.	Manufacturer	Calibration Date	Calibration Cycle
Ultra Compact	UCS 500				
Simulator	M4	0304-42	EM TEST	2020.06.01	1Year
Power Source MV2616		0104-14	EM TEST	2020.06.01	1Year

2.8 Conducted Immunity Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave					
Simulator	CWS 500C	0407-05	EM TEST	2020.06.01	1 Year

Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave	UCS 500 M4	0304-42	EM TEST	2020.06.01	1 Year
Simulator	UCS 300 M4	0304-42	EMIESI	2020.00.01	1 Tear
Power Source	MV 2616	0104-14	EM TEST	2020.06.01	1 Year
Network	MIV 2010	0104-14	EMIESI	2020.06.01	1 Tear
Current Transformer	MC2630		EM TEST	2020.06.01	1 Year

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Magnetic Coil	MS100	0304-42	EM TEST	2020.06.01	1 Year

2.10 Voltage Dips/Interruption Immunity Test

	1	7			
				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact					
Simulator	UCS 500 M4	0304-42	EM TEST	2020.06.01	1Year
Power Source	MV2616	0104-14	EM TEST	2020.06.01	1Year

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3.0 Technical Details

3.1 Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility[EMS] tests for CE Marking

3.2 Test Standards

	Test Standards						
EN 55032:2015	Electromagnetic compatibility of multi	media equipment - Emission Requirements					
EN61000-3-2:2014	Electromagnetic compatibility(EMC)-	Part 3-2:Limits-Limits for harmonic current					
EN01000-3-2.2014	emissions(equipment input current ≤	16A per phase)					
	Electromagnetic compatibility (EMC	C)- Part 3-3:Limits-Limitation of voltage					
EN 61000-3-3:2013	changes, Voltage fluctuations and flick	er in public low-voltage supply systems. For					
EN 01000-3-3.2013	equipment with rated current ≤16A per phase and not subject to conditional						
	connection						
EN	Information technology equipment — Immunity characteristics — Limits and						
55024:2010+A1:2015	methods of measurement						
	EN 61000-4-2:2009	Electrostatic discharge					
	EN 61000-4-3:2006	RF field strength susceptibility					
	EN 61000-4-4:2012	Electrical Fast transients					
	EN 61000-4-5:2014	Surge					
	EN 61000-4-6:2009	Conducted susceptibility					
	EN 61000-4-8:2010	Power-frequency Magnetic Field					
	EN 61000-4-11:2004	Dips/Voltage Interruption Variation					

3.3 Performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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3.4 Test standards and Results Summary Tables

Test Condition	Test Requirement	Test Method	Test Result						
	EMISSION Results Summary								
Conducted Emission on AC Mains,	EN 55032:2015	EN 55032:2015	Pass						
150kHz to 30MHz			Pass						
Conducted Emission on at	EN 55032:2015	EN 55032:2015							
telecommunication ports,			N/A						
150KHz to 30MHz									
Radiated Emissions,	EN 55032:2015	EN 55032:2015	Pass						
30MHz to 1GHz			rass						
Harmonic Emissions on AC supply	EN61000-3-2:2014	EN61000-3-2:2014	N/A						
Voltage fluctuations on AC supply	EN 61000-3-3: 2013	EN 61000-3-3: 2013	N/A						
	IMMUNITY Results Sum	mary							
Electrostatic Discharge	EN 55024: 2010+A1:2015	EN 61000-4-2: 2009	Pass						
Electrical Fast transients	EN 55024: 2010+A1:2015	EN 61000-4-4: 2012	Pass						
/Burst Immunity			Pass						
RF field strength susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-3: 2006	Pass						
Surge	EN 55024: 2010+A1:2015	EN 61000-4-5: 2014	Pass						
Conducted susceptibility	EN 55024: 2010+A1:2015	EN 61000-4-6: 2009	Pass						
Power-frequency Magnetic Field	EN 55024: 2010+A1:2015	EN61000-4-8: 2010	N/A						
Dips/Voltage Interruption Variation	EN 55024: 2010+A1:2015	EN 61000-4-11: 2004	Pass						

Note: N/A-Not applicable

Date: 2020-06-19

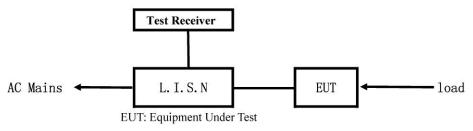


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4.0 Electromagnetic Interference Test results

4.1 Power line Conducted Emission Test

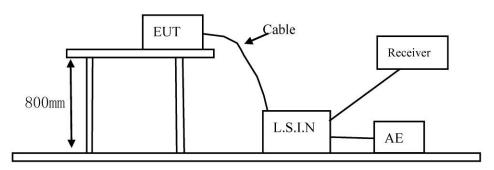
4.1.1 Schematics of the test



4.1.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.1.3 Power line conducted Emission Limit

	Limits dB(μ V)						
Frequency(MHz)	Class A l	Equipment	Class B E	quipment			
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level			
0.15 ~ 0.50	79.0	66.0	66.0~56.0*	56.0~46.0*			
0.50 ~ 5.00	73.0	60.0	56.0	46.0			
5.00 ~ 30.00	73.0	60.0	60.0	50.0			

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The lower limit shall apply at the transition frequencies

4.1.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=3.6dB

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A: Conducted Emission on Live Terminal (150kHz to 30MHz)

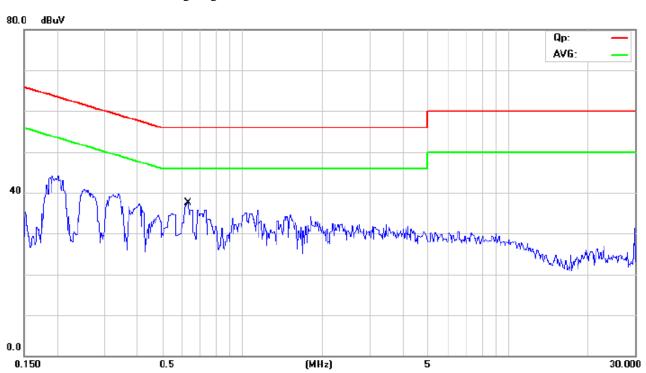
EUT Operating Environment

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



No.	Mk.	Freq.	Reading Level		Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1	*	0.6240	22.40	10.43	32.83	56.00	-23.17	QP	
2		0.6240	-1.90	10.43	8.53	46.00	-37.47	AVG	

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B: Conducted Emission on Neutral Terminal (150kHz to 30MHz)

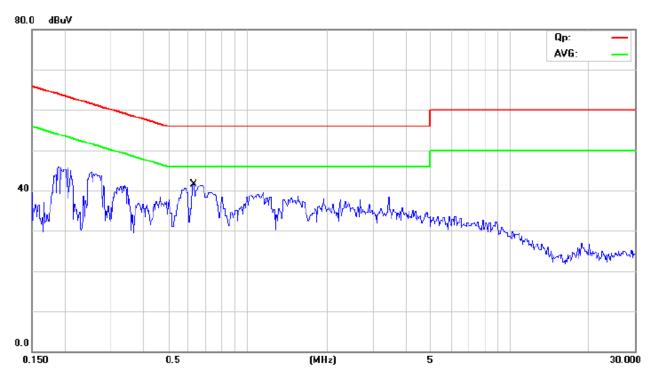
EUT Operating Environment

Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1	*	0.6251	27.40	10.43	37.83	56.00	-18.17	QP	
2		0.6251	1.40	10.43	11.83	46.00	-34.17	AVG	

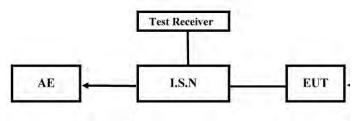
Date: 2020-06-19



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4.2 Telecommunication ports Conducted Emission Test

4.2.1 Schematics of the test

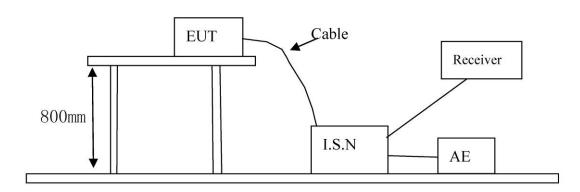


EUT: Equipment Under Test

4.2.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.2.3 Telecommunication ports conducted Emission Limit

	Class A Limits				Class B Limits				
Frequency(MHz)	Quasi-pe	Quasi-peak Level		Average Level		Quasi-peak Level		Average Level	
r requency(whrz)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)	Vlotage dB(uV)	Current dB(uA)	
0.15 ~ 0.50	97 to 87	53 to43	84 to74	40 to 30	84 to 74	40 to30	74 to64	30 to 20	
0.50 ~ 30.00	87	43	74	30	74	30	64	20	

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The tighter limit shall apply at the transition frequencies

4.2.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=1.9dB

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A: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBμV)	Limit(dBµV)	
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average
	LAN				
	LAN				

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B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: ClassB

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBμA)	Limit(dBµA)		
(MHz)	FOIL	Quasi-peak	Average	Quasi-peak	Average	
	LAN					

Note: No such port, not applicable.

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4.3 Radiated Disturbance Test

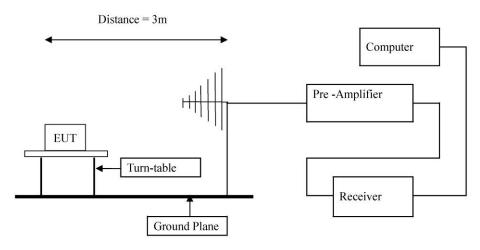
4.3.1 Schematics of the test



4.3.2 Test Method:

The test was performed in accordance with EN 55032:2015

Block diagram of Test setup



4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB µ V/m)		
	Class A Limits	Class B Limits	
30-230	50.00	40.00	
230-1000	57.00	47.00	

Note: The lower limit shall apply at the transition frequencies

4.3.4 Test result

Limits for Radiated Disturbance test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

Remark:

Calculated measurement uncertainty=4.7dB

Date: 2020-06-19



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A: Radiated Disturbance (30MHz----1000MHz)

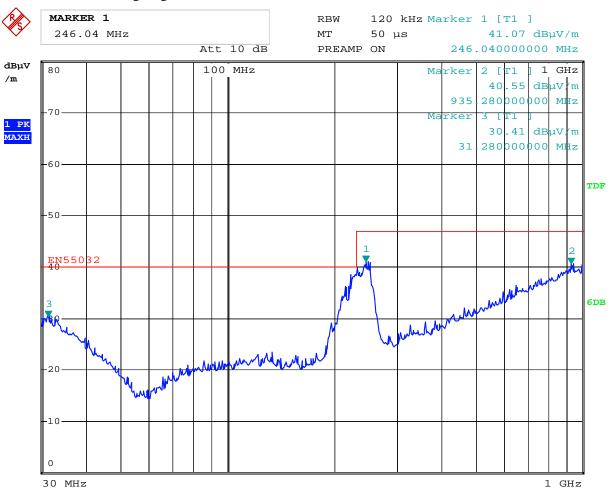
EUT Operating Environment

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



Date: 11.DEC.2019 17:08:38

Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m (dBµV/m)
246.040	41.07	Н	47.00
935.280	40.55	Н	47.00
31.280	30.41	Н	40.00

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B: Radiated Disturbance (30MHz----1000MHz)

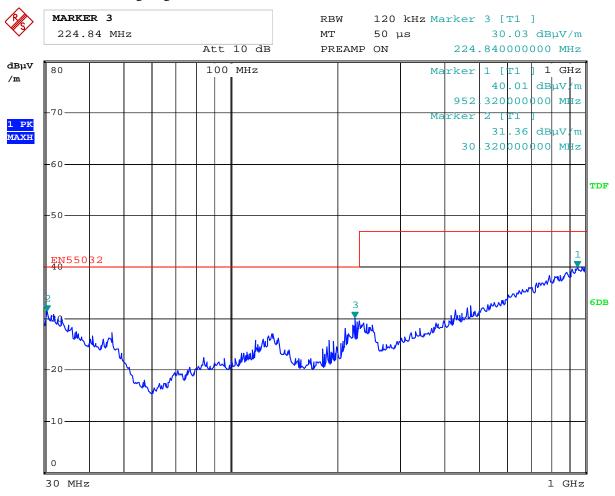
EUT Operating Environment

Temperature: 25°C Humidity: 55%RH Atmospheric Pressure: 101 kPa

EUT set Condition: Charging Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



Date: 11.DEC.2019 17:11:25

Frequency (MHz)	Level@3m ($dB\mu V/m$)	Antenna Polarity	Limit@3m ($dB\mu V/m$)
224.840	30.03	V	40.00
952.320	40.01	V	47.00
30.320	31.36	V	40.00

Note: Pre-scanning with PK detector and final measurement with QP detector

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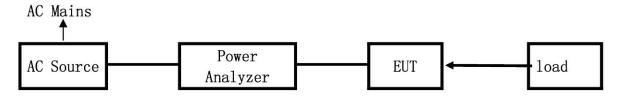
Date: 2020-06-19



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4.4 Harmonic Current Emission Test

4.4.1 Schematic of the test



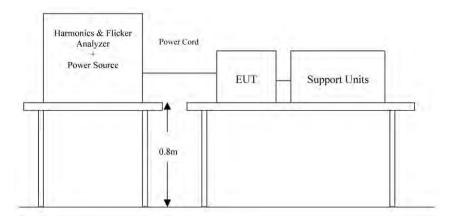
EUT: Equipment Under Test

4.4.2 Test Method:

The test was performed in accordance with EN61000-3-2:2014

*: The Level of the product is : CLASS D

Block diagram of Test setup



4.4.3 Limits of Harmonic Current Emission For Class A

Harmonic order	Maximum permissible harmonic current		
n	A		
Odd h	narmonics		
3	2,30		
5	1,14		
7	0,77		
9	0,40		
11	0,33		
13	0,21		
$15 \leq n \leq 39$	0.15 15 n		
Even	harmonics		
2	1,08		
4	0,43		
6	0,30		
$8 \le n \le 40$	0,23 8 n		

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4.4.4 Test Results

Please refer to the following pages

Harmonic Current Emission Test

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

EUT set Condition:

Results: N/A

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		result/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

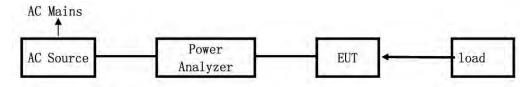
Date: 2020-06-19



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4.5 Voltage Fluctuations & Flicker Test

4.5.1 Schematic of the test

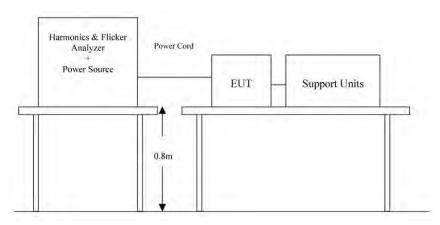


EUT: Equipment Under Test

4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013

Block diagram of Test setup



Date: 2020-06-19



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4.5.3 Test Results

Result: N/A

Please refer to following diagram for individual

Maximum Occurring Levels:

Ut: 230.1 (EUT Test RMS Voltage)

Pst:	Limit=	1.0	(The Highest short Term Flicker Value)
Plt:	Limit=	0.65	(The Highest Long Term Flicker Value)
dt(%):	Limit=	3.3%	(The Highest instantaneous Voltage Change (10ms))
dc(%):	Limit=	3.3%	(The highest Relative steady state voltage change (1sec))
dmax:	Limit=	4%	(The highest Max Relative voltage change)
Tdt:	Limit=	500ms	(The Max Time(in milli-sec) that dt exceeds 3%)

Date: 2020-06-19

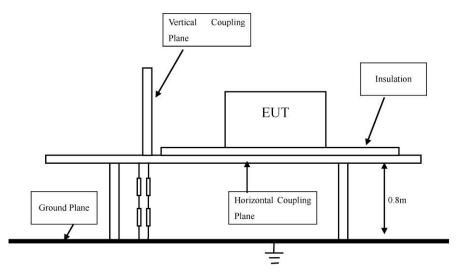


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5.0 Immunity Test

5.1 Electrostatic Discharge

5.1.1 Schematic of the test



5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

5.1.3 Test severity

- ±4Kv for direct & in-direct Contact Discharge
- ± 8 Kv for air Discharge

Performance Criterion Require: **B** (Please see following table)

5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (Kv)	discharge(Kv)
1	±2Kv	±2Kv
2	±4Kv	±4Kv
3	±6Kv	±8Kv
4	±8Kv	±15Kv

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5.1.5 Test Result

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 Kpa

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
НСР	In-Direct	$\pm 2kV, \pm 4kV$	Pass
VCP	In-Direct	$\pm 2kV, \pm 4kV$	Pass
Screw	Contact Discharge	$\pm 2kV, \pm 4kV$	Pass
Function key	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Gap	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Enclosure	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Cable	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass
Near USB port	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

Remark: Calculated measurement uncertainty= 0.2kV

Date: 2020-06-19



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5.2 RF field strength susceptibility (80MHz----- 1000MHz)

5.2.1 Schematics of the test



EUT: Equipment Under Test

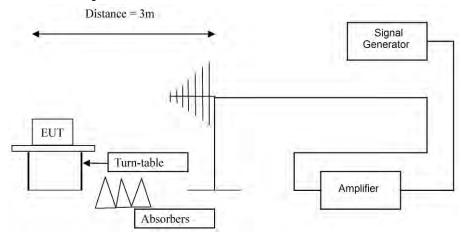
5.2.2 Test Method:

The test was performed in accordance with EN 61000-4-3:2006

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Field Strength (V/m)
1	1
2	3
3	10

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5.2.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Frequency (MHz)	Face	Polarity	Level (V/m)	Dwell Time(s)	Sweep Rate (%)	Results
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass

Remark: Calculated measurement uncertainty= 80MHz to 1000MHz (+3.7/ -1.3) V/m

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5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

5.3.1 Schematics of the test



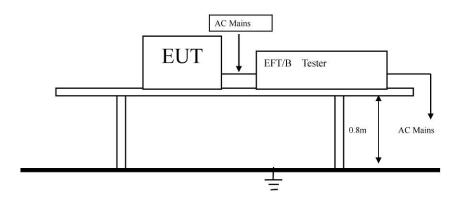
5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: **B** (Please see following table)

Block diagram of Test setup



5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

	Open Circuit output Test Voltag	e ±10%
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

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5.3.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to following page.

Inject location: AC mains

Inject Line	Voltage kV	Inject Times (s)	Method	Results
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

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atc. 2020-00-1)

5.4 Surge test

5.4.1 Schematics of the test



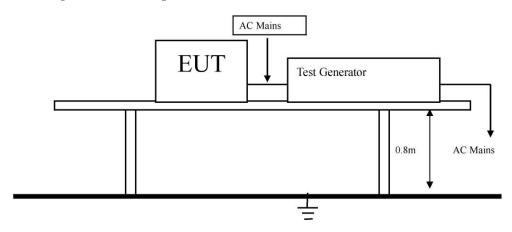
5.4.2 Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

Severity Level	Open-Circuit Test Voltage
	kV
1	0.5
2	1.0
3	2.0
4	4.0
*	Special

5.4.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to following page.

Test location:

Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
	±	0	5	1.0	Pass
I NI	<u>±</u>	90	5	1.0	Pass
L-N	<u>±</u>	180	5	1.0	Pass
	±	270	5	1.0	Pass

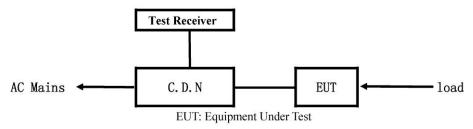
Date: 2020-06-19



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5.5 Conducted Immunity test

5.5.1 Schematics of the test



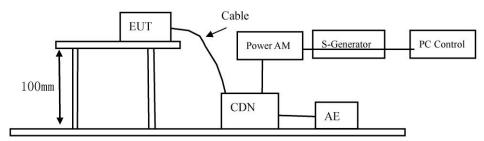
5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2009

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Voltage Level (e.m.f) V
1	1
2	3
3	10
*	Special

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5.5.4 Test Results:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

Frequency Range (MHz)	Injected Position	Strength	Criterion	Observation	Result
0.15 - 20	AC Line	3V (rms) Unmodulated	A	A	Pass
20 - 80	AC Line	3V (rms) Unmodulated	A	A	Pass

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5.6 Power-Frequency magnetic field test

5.6.1 Schematics of the test



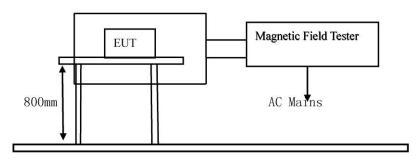
5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Magnetic Field Strength A/m	
1	1	
2	3	
3	10	
4	30	
5	100	
*	Special	

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5.6.4 Test Results:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

		6 F -6 -			
Test L	evel Test	ing Duration	Coil Orientation	Criterion	Result
1A/	m	5 Mins	X	A	N/A
1A/	m	5 Mins	Y	A	N/A
1A/	m	5 Mins	Z	A	N/A

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5.7 Voltage Dips/Interruptions immunity test

5.7.1 Schematics of the test

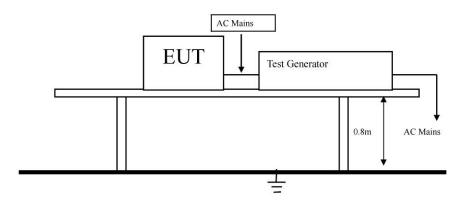


5.7.2 Test Method:

The test was performed in accordance with EN 61000-4-11:2004

Performance Criterion Require: C&B (Please see following table)

Block diagram of Test setup



5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
С	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

	Test Level %Ut	Reduction	Duration	Performance				
Voltage Dip			(Periods)	Criteria				
	<5	>95	0.5	В				
	70	30	25	C				
Voltage Interceptions	Test Level %Ut	Reduction	Duration	Performance				
			(Periods)	Criteria				
	<5	>95	250	C				

5.7.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following page

Voltage Dip:

Test Level	Reduction	Duration	Phase Angle	Meet	Result
% Ut		(periods)		Criterion	
0	100	0.5	0° - 360°	A	Pass
70	30	25	0° - 360°	A	Pass

Voltage Interceptions:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° - 360°	В	Pass

Date: 2020-06-19



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6.0 Product Labelling

6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

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7.0 Photo of testing





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Photo for the EUT





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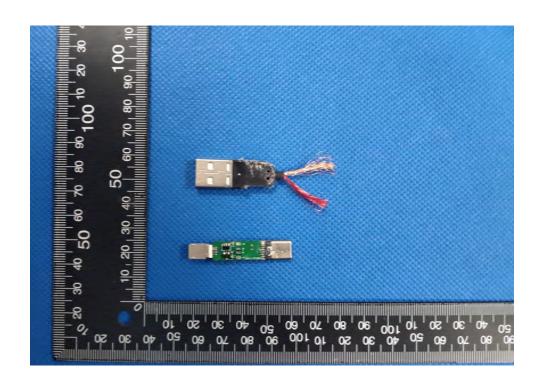
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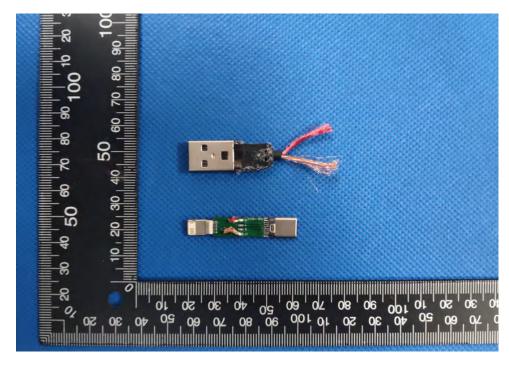
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Photo for the EUT





-End of the report-

The report refers only to the sample tested and does not apply to the bulk.

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